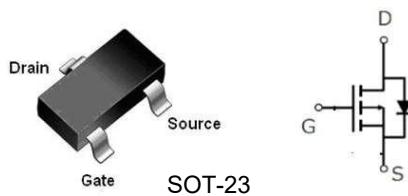


P-Channel PowerTrench® MOSFET

-20V, -5A, 35mΩ

Features

- $R_{DS(ON)} = 35\text{m}\Omega$ @ $V_{GS} = -10\text{ V}$
- $R_{DS(ON)} = 43\text{m}\Omega$ @ $V_{GS} = -4.5\text{ V}$



Order Information

Product	Package	Marking	Packing	Min Unit Quantity
IRLML6401	SOT-23	34**	3000PCS/Reel	3000PCS

ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^\circ\text{C}$, unless otherwise noted)				
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	- 20		
Gate-Source Voltage	V_{GS}	± 12	V	
Continuous Drain Current ($T_J = 150\text{ }^\circ\text{C}$)	I_D	$T_C = 25\text{ }^\circ\text{C}$	- 5 ^e	A
		$T_C = 70\text{ }^\circ\text{C}$	- 4.8	
		$T_A = 25\text{ }^\circ\text{C}$	- 4.5 ^{b, c}	
		$T_A = 70\text{ }^\circ\text{C}$	- 3.5 ^{b, c}	
Pulsed Drain Current	I_{DM}	- 18		
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^\circ\text{C}$	- 2.1	W
		$T_A = 25\text{ }^\circ\text{C}$	- 1.0 ^{b, c}	
Maximum Power Dissipation	P_D	$T_C = 25\text{ }^\circ\text{C}$	2.5	
		$T_C = 70\text{ }^\circ\text{C}$	1.6	
		$T_A = 25\text{ }^\circ\text{C}$	1.25 ^{b, c}	
		$T_A = 70\text{ }^\circ\text{C}$	0.8 ^{b, c}	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	R_{thJA}	75	100	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	40	

Notes:

- a. Based on $T_C = 25\text{ }^\circ\text{C}$.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 5 s.
- d. Maximum under steady state conditions is 166 °C/W.
- e. Package limited.

MOSFET SPECIFICATIONS ($T_J = 25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{DS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-20			V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250 \mu\text{A}$		-13.4		mV/ $^\circ\text{C}$	
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			2.9			
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	-0.5		-1.5	V	
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μA	
		$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			-10		
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \leq -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	-18			A	
Drain-Source On-State Resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = -10 \text{ V}, I_D = -5.1 \text{ A}$		0.035		Ω	
		$V_{GS} = -4.5 \text{ V}, I_D = -4.5 \text{ A}$		0.043			
		$V_{GS} = -2.5 \text{ V}, I_D = -3.7 \text{ A}$		0.061			
Forward Transconductance ^a	g_{fs}	$V_{DS} = -5 \text{ V}, I_D = -5.1 \text{ A}$		15		S	
Dynamic^b							
Input Capacitance	C_{iss}	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		835		pF	
Output Capacitance	C_{oss}			180			
Reverse Transfer Capacitance	C_{rss}			155			
Total Gate Charge	Q_g	$V_{DS} = -10 \text{ V}, V_{GS} = -4.5 \text{ V}, I_D = -5.1 \text{ A}$		10		nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = -10 \text{ V}, V_{GS} = -2.5 \text{ V}, I_D = -5.1 \text{ A}$		6.4			
Gate-Drain Charge	Q_{gd}			1.7			
Gate Resistance	R_g		$f = 1 \text{ MHz}$	3.4			
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = -10 \text{ V}, R_L = 2.4 \Omega$ $I_D = -4.1 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		0.9	4.4	8.8	Ω
Rise Time	t_r				22	33	ns
Turn-Off Delay Time	$t_{d(\text{off})}$				20	30	
Fall Time	t_f				28	42	
					9	18	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			-2.1	A	
Pulse Diode Forward Current ^a	I_{SM}				-20		
Body Diode Voltage	V_{SD}	$I_S = -4.1 \text{ A}$		-0.8	-1.2	V	
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -4.1 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		23	35	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			12	20	nC	
Reverse Recovery Fall Time	t_a			15		ns	
Reverse Recovery Rise Time	t_b			8			

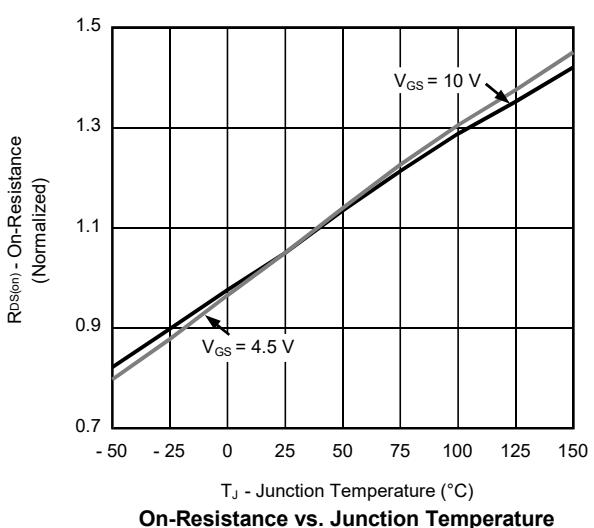
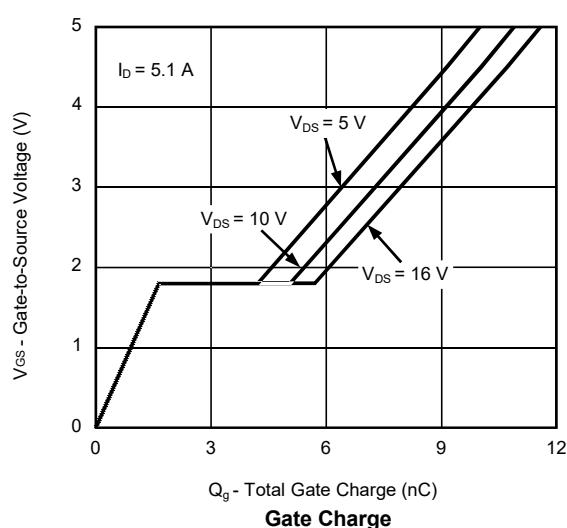
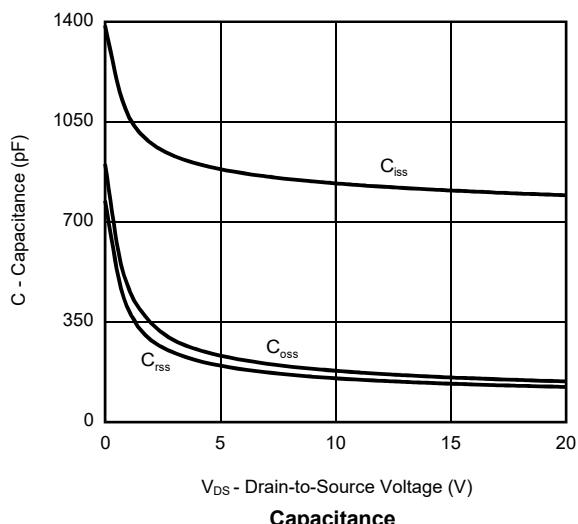
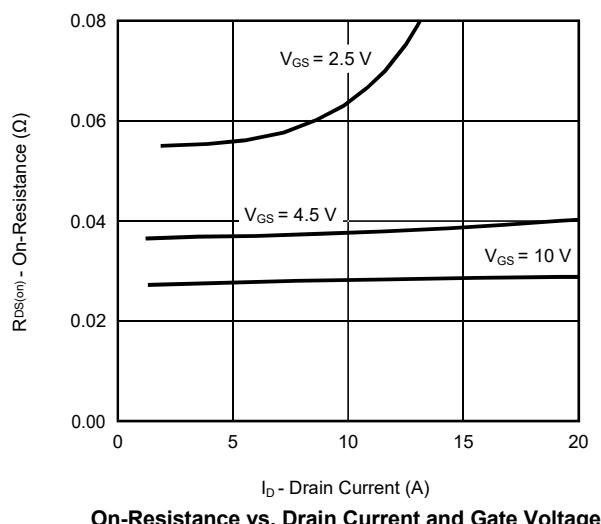
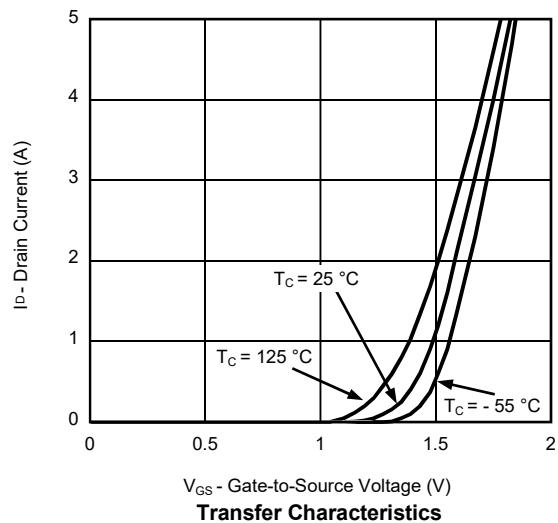
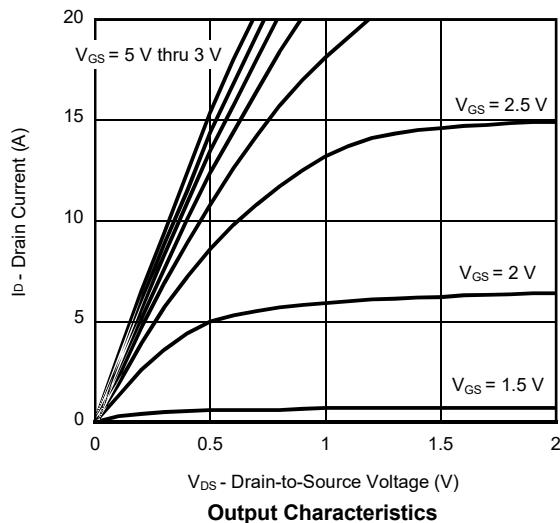
Notes:

a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

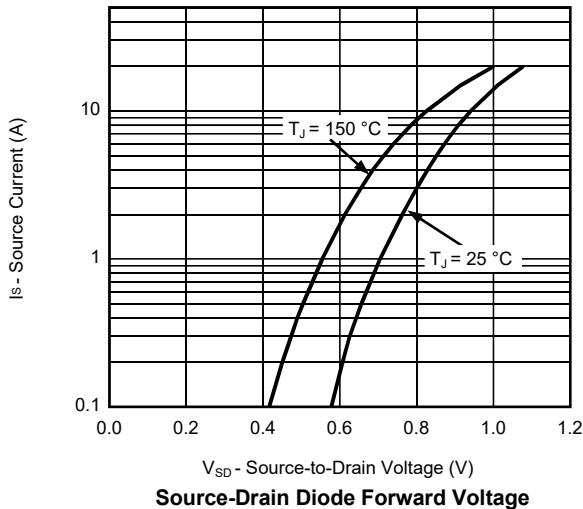
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

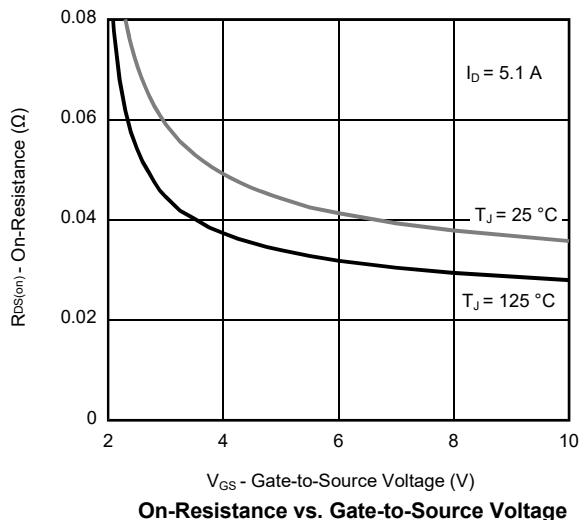
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



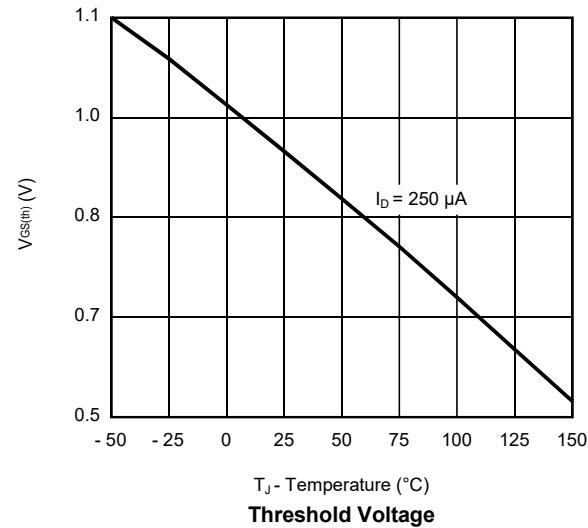
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



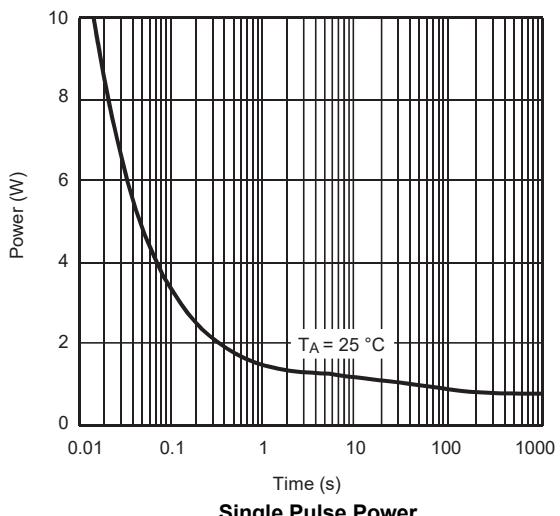
Source-Drain Diode Forward Voltage



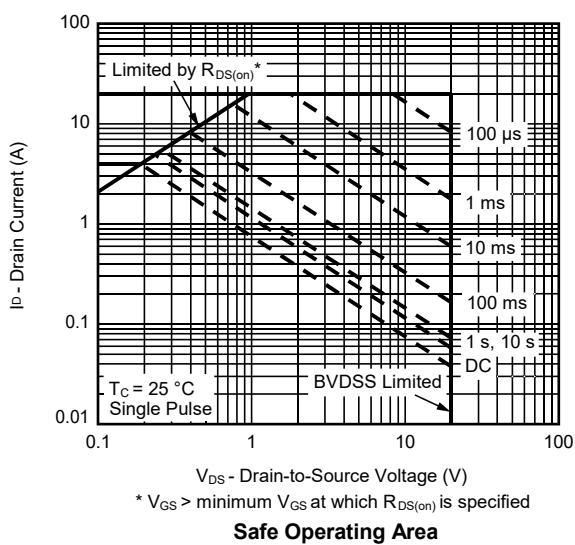
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

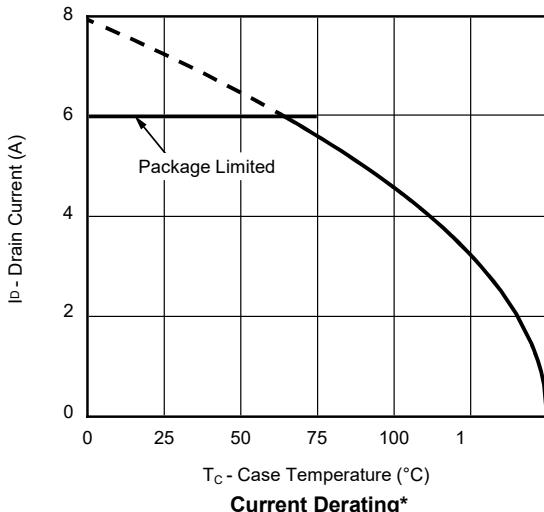


Single Pulse Power



Safe Operating Area

* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified



Current Derating*

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

